Power MOSFET

40 V, 70 A, Single N-Channel, DPAK

Features

- Low R_{DS(on)}
- High Current Capability
- Low Gate Charge
- AEC–Q101 Qualified and PPAP Capable STD5406N
- These Devices are Pb-Free and are RoHS Compliant

Applications

- Electronic Brake Systems
- Electronic Power Steering
- Bridge Circuits

6 (T _J = 25°	C unless other	rwise stated	d)	
neter		Symbol	Value	Unit
e		V _{DSS}	40	V
е		V _{GS}	±20	V
Steady	$T_{C} = 25^{\circ}C$	I _D	70	Α
State	$T_{C} = 125^{\circ}C$		40	
Steady State	$T_{C} = 25^{\circ}C$	P _D	100	W
Steady State	$T_A = 25^{\circ}C$	I _D	12.2	Α
	T _A = 125°C		7.0	
Steady State	$T_A = 25^{\circ}C$	P _D	3.0	W
t _p =	= 10 μs	I _{DM}	150	Α
Storage T	emperature	T _J , T _{STG}	–55 to 175	°C
Source Current (Body Diode) Pulsed				Α
		EAS	450	mJ
	urposes	ΤL	260	°C
	e Steady State Steady State Steady State Steady State Steady State tp = Storage T	$\begin{array}{c} \text{neter} \\ \text{je} \\ \text{e} \\ \\ \hline \\ State \\ \hline \\ T_{C} = 25^{\circ}C \\ \hline \\ T_{C} = 125^{\circ}C \\ \hline \\ T_{C} = 25^{\circ}C \\ \hline \\ Steady \\ State \\ \hline \\ T_{A} = 25^{\circ}C \\ \hline \\ T_{A} = 125^{\circ}C \\ \hline \\ Steady \\ State \\ \hline \\ T_{A} = 25^{\circ}C \\ \hline \\ T_{A} = 125^{\circ}C \\ \hline \\ Steady \\ State \\ \hline \\ T_{C} = 25^{\circ}C \\ \hline \\ T_{A} = 25^{\circ}C \\ \hline \\ Steady \\ State \\ \hline \\ T_{C} = 25^{\circ}C \\ \hline \\ T_{A} = 25^{\circ}C \\ \hline \\ Steady \\ State \\ \hline \\ T_{C} = 25^{\circ}C \\ \hline \\ T_{A} = 125^{\circ}C \\ \hline \\ Steady \\ State \\ \hline \\ Steady \\ State \\ \hline \\ T_{C} = 25^{\circ}C \\ \hline \\ T_{A} = 25^{\circ}C \\ \hline \\ \hline \\ Steady \\ State \\ \hline \\ T_{C} = 25^{\circ}C \\ \hline \\ \hline \\ T_{C} = 25^{\circ}C \\ \hline \\ \hline \\ Steady \\ State \\ \hline \\ \hline \\ Steady \\ \hline \\ \\ Steady \\ \hline \\ \\ Steady \\ \hline \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ $	Symbol Ide VDSS Ide VDSS Ide TC = 25°C Steady State TC = 25°C Steady State TC = 25°C Steady State TA = 25°C IDM Storage Temperature TJ, TSTG Diode) Pulsed Is Source Avalanche /GS = 10 V, IPK = 30 A, EAS oldering Purposes TI	$\begin{array}{c c c c c c c c c c c c c c c c c c c $

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

THERMAL RESISTANCE RATINGS (Note 1)

Parameter	Symbol	Мах	Unit
Junction-to-Case (Drain)	$R_{\theta JC}$	1.5	°C/W
Junction-to-Ambient (Note 1)	$R_{\theta JA}$	49	

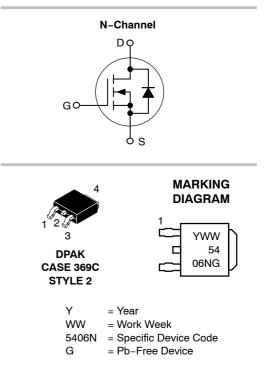
1. Surface mounted on FR4 board using 1 sq in pad size, (Cu Area 1.127 sq in [2 oz] including traces).



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V _{(BR)DSS}	R _{DS(ON)} TYP	I _D MAX (Note 1)
40 V	8.7 m Ω @ 10 V	70 A



ORDERING INFORMATION

Device	Package	Shipping†
NTD5406NT4G	DPAK (Pb–Free)	2500 / Tape & Reel
STD5406NT4G	DPAK (Pb-Free)	2500 / Tape & Reel

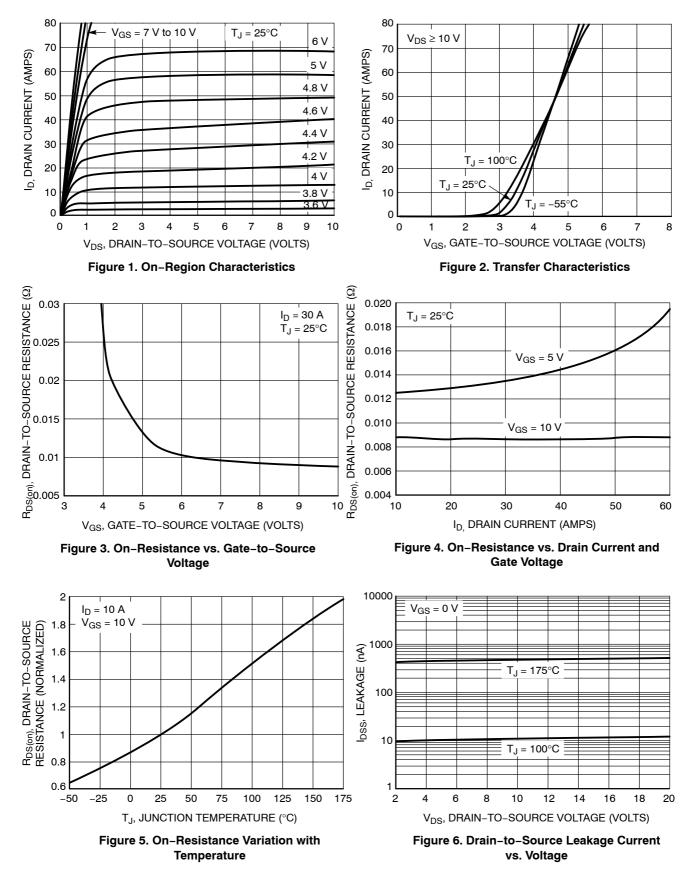
†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

ELECTRICAL CHARACTERISTICS (T_J = 25° C unless otherwise stated)

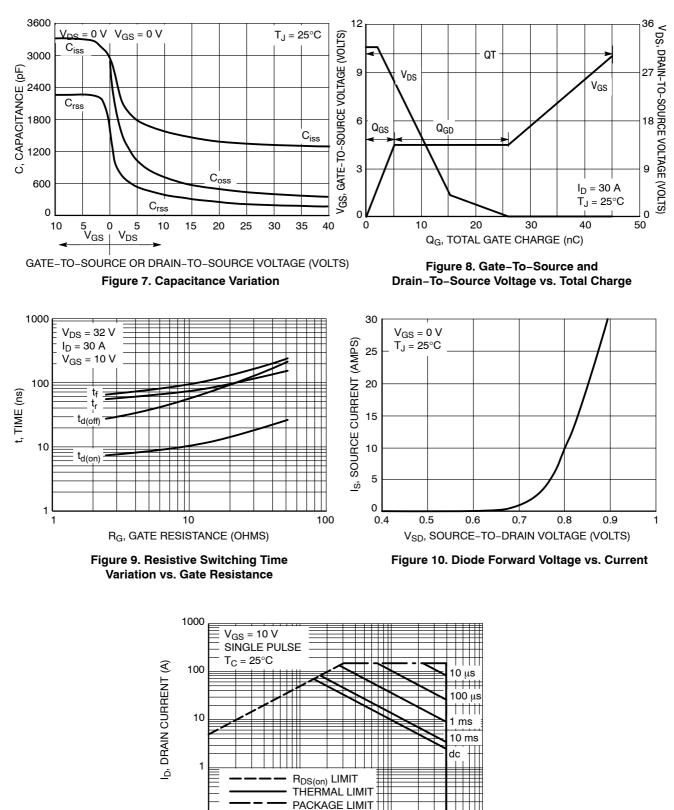
Parameter	Symbol	Test Condition		Min	Тур	Max	Unit	
OFF CHARACTERISTICS								
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 V, I_D$	= 250 μA	40			V	
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /T _J				42		mV/°C	
Zero Gate Voltage Drain Current	I _{DSS}	V _{GS} = 0 V,	$T_J = 25^{\circ}C$		1	1.0	μΑ	
		$V_{DS} = 40 V$	$T_J = 100^{\circ}C$		1	10		
Gate-to-Source Leakage Current	I _{GSS}	V _{DS} = 0 V, V ₀	_{àS} = ±30 V		1	±100	nA	
ON CHARACTERISTICS (Note 2)								
Gate Threshold Voltage	V _{GS(TH)}	V _{GS} = V _{DS} , I _E	₀ = 250 μA	1.5		3.5	V	
Gate Threshold Temperature Coefficient	V _{GS(TH)} /T _J				-7.0		mV/°C	
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V,	I _D = 30 A		8.7	10	mΩ	
		V _{GS} = 5.0 V,	l _D = 10 A		13.2	17		
Forward Transconductance	9 FS	V _{GS} = 10 V,	I _D = 10 A		19		S	
CHARGES AND CAPACITANCES					•		-	
Input Capacitance	C _{ISS}				1375	2500	pF	
Output Capacitance	C _{OSS}	V _{GS} = 0 V, f = V _{DS} = 3	1.0 MHz, 32 V		370	700		
Reverse Transfer Capacitance	C _{RSS}	•DS - •			160	300		
Total Gate Charge	Q _{G(TOT)}				45		nC	
Threshold Gate Charge	Q _{G(TH)}	V _{GS} = 10 V, V	_{DS} = 32 V,		2.0		1	
Gate-to-Source Charge	Q _{GS}	$I_{\rm D} = 30 \text{ A}$			5.4			
Gate-to-Drain Charge	Q _{GD}				20			
SWITCHING CHARACTERISTICS, VG	is = 10 V (Note :	3)						
Turn-On Delay Time	t _{d(ON)}				7.2		ns	
Rise Time	t _r	V _{GS} = 10 V, V	_{DD} = 32 V,		57			
Turn-Off Delay Time	t _{d(OFF)}	I _D = 30 A, R	_G = 2.5 Ω		30			
Fall Time	t _f				67			
SWITCHING CHARACTERISTICS, VG	is = 5 V (Note 3))						
Turn-On Delay Time	t _{d(ON)}				15		ns	
Rise Time	t _r	V_{GS} = 5.0 V, V_{DD} = 20 V, I_{D} = 30 A, R_{G} = 2.5 Ω			147			
Turn-Off Delay Time	t _{d(OFF)}				20			
Fall Time	t _f				29			
DRAIN-SOURCE DIODE CHARACTE	RISTICS							
Forward Diode Voltage	V _{SD}	V _{GS} = 0 V,	$T_J = 25^{\circ}C$		0.82	1.1	V	
		$I_{\rm S} = 10$ A	T _J = 125°C		0.67			
Reverse Recovery Time	t _{RR}	V _{GS} = 0 V, dI _{SD} /dt = 100 A/µs, I _S = 10 A			46		ns	
Charge Time	t _a				24			
Discharge Time	t _b				22			
Reverse Recovery Charge	Q _{RR}		Ē		65		nC	

Pulse Test: pulse width ≤ 300 μs, duty cycle ≤ 2%.
 Switching characteristics are independent of operating junction temperatures.

TYPICAL PERFORMANCE CURVES



TYPICAL PERFORMANCE CURVES



V_{DS}, DRAIN-TO-SOURCE VOLTAGE (V) Figure 11. Maximum Rated Forward Biased Safe Operating Area

10

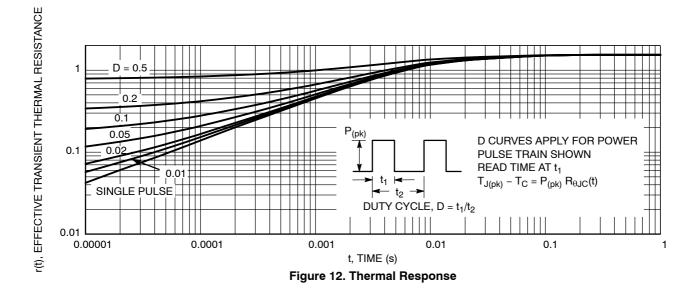
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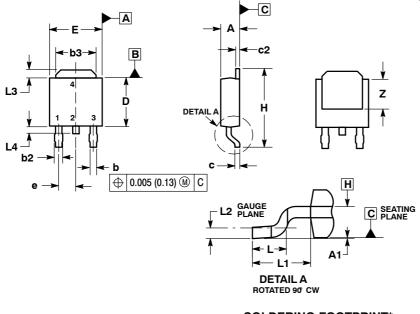
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TYPICAL PERFORMANCE CURVES



PACKAGE DIMENSIONS

DPAK (SINGLE GAUGE) CASE 369C **ISSUE D**

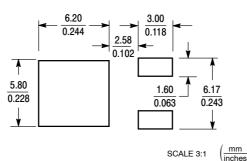


NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994
- CONTROLLING DIMENSION: INCHES.
 THERMAL PAD CONTOUR OPTIONAL WITHIN DI-MENSIONS b3, L3 and Z. 4. DIMENSIONS D AND E DO NOT INCLUDE MOLD
- FLASH, PROTRUSIONS, OR BURRS, MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL
- NOT EXCEED 0.006 INCHES PER SIDE. 5. DIMENSIONS D AND E ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- 6. DATUMS A AND B ARE DETERMINED AT DATUM PLANE H.

	INCHES		MILLIN	ETERS		
DIM	MIN	MAX	MIN	MAX		
Α	0.086	0.094	2.18	2.38		
A1	0.000	0.005	0.00	0.13		
b	0.025	0.035	0.63	0.89		
b2	0.030	0.045	0.76	1.14		
b3	0.180	0.215	4.57	5.46		
с	0.018	0.024	0.46	0.61		
c2	0.018	0.024	0.46	0.61		
D	0.235	0.245	5.97	6.22		
E	0.250	0.265	6.35	6.73		
е	0.090	BSC	2.29 BSC			
н	0.370	0.410	9.40	10.41		
L	0.055	0.070	1.40	1.78		
L1	0.108 REF		2.74	74 REF		
L2	0.020 BSC		0.51	BSC		
L3	0.035	0.050	0.89	1.27		
L4		0.040		1.01		
Z	0.155		3.93			

SOLDERING FOOTPRINT*



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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